

PSMN2R2-25YLC

N-channel 25 V 2.4 m Ω logic level MOSFET in LFPAK using NextPower technology

Rev. 1 — 2 May 2011

Product data sheet

1. Product profile

1.1 General description

Logic level enhancement mode N-channel MOSFET in LFPAK package. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

1.2 Features and benefits

- High reliability Power SO8 package, qualified to 175°C
- Low parasitic inductance and resistance

1.3 Applications

- DC-to-DC converters
- Lithium-ion battery protection
- Load switching

1.4 Quick reference data

Table 1. Quick reference data

- Optimised for 4.5V Gate drive utilising NextPower Superjunction technology
- Ultra low QG, QGD and QOSS for high system efficiencies at low and high loads
- Power OR-ing
- Server power supplies
- Sync rectifier

	Quick reference c					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	25 °C ≤ T _j ≤ 175 °C	-	-	25	V
I _D	drain current	T _{mb} = 25 °C; V _{GS} = 10 V; see <u>Figure 1</u>	<u>[1]</u> _	-	100	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	106	W
Tj	junction temperature		-55	-	175	°C
Static cha	racteristics					
R _{DSon}	drain-source on-state	V _{GS} = 4.5 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 12</u>	-	2.6	3.15	mΩ
	resistance	V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 12</u>	-	2	2.4	mΩ



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Table 1.	Quick reference dat	acontinued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$\label{eq:VGS} \begin{array}{l} V_{GS} = 4.5 \; V; \; I_{D} = 25 \; A; \\ V_{DS} = 12 \; V; \; see \; \underline{Figure \; 14}; \\ see \; \underline{Figure \; 15} \end{array}$	-	5.2	-	nC
Q _{G(tot)}	total gate charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \underline{\text{Figure } 15};$ $\text{see } \underline{\text{Figure } 14}$	-	18	-	nC

[1] Continuous current is limited by package

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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		-
2	S	source	mb	
3	S	source		
4	G	gate	Q	d - t - t - t - t - t - t - t - t - t -
mb	D	mounting base; connected to drain	$\begin{array}{c} \begin{array}{c} \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\$	mbb076 S
			SOT669 (LFPAK;	

Power-SO8)

3. Ordering information

Table 3. Ordering	ering information				
Type number	Package				
	Name	Description	Version		
PSMN2R2-25YLC	LFPAK; Power-SO8	plastic single-ended surface-mounted package; 4 leads	SOT669		

4. Marking

Table 4. Marking codes	
Type number	Marking code ^[1]
PSMN2R2-25YLC	2C225L

[1] % = placeholder for manufacturing site code.

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5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

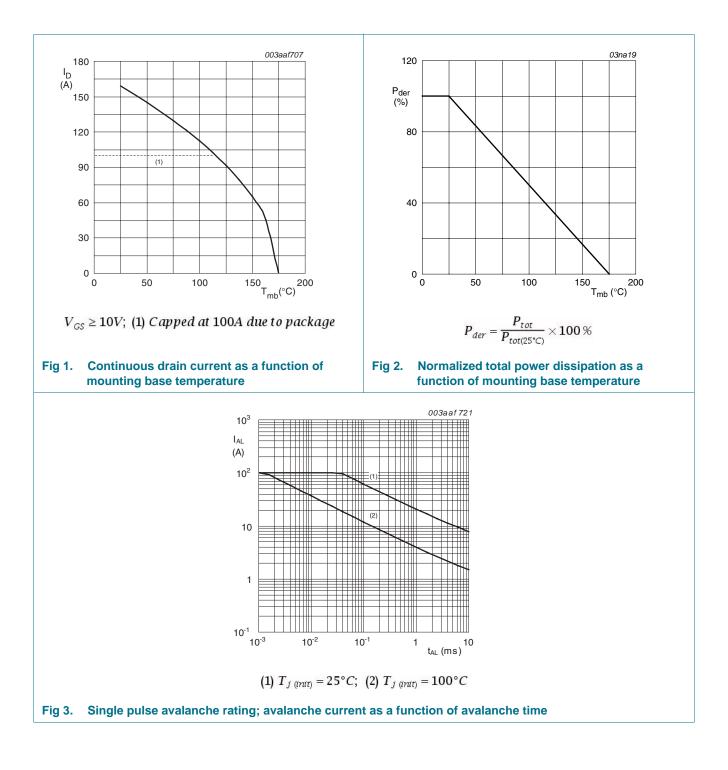
Parameter	Conditions	Min	Max	Unit
drain-source voltage	25 °C ≤ T _j ≤ 175 °C	-	25	V
drain-gate voltage	25 °C \leq T _j \leq 175 °C; R _{GS} = 20 k Ω	-	25	V
gate-source voltage		-20	20	V
drain current	V_{GS} = 10 V; T_{mb} = 25 °C; see <u>Figure 1</u>	<u>[1]</u> _	100	А
	V_{GS} = 10 V; T_{mb} = 100 °C; see <u>Figure 1</u>	<u>[1]</u> _	100	А
peak drain current	pulsed; t _p ≤ 10 µs; T _{mb} = 25 °C; see <u>Figure 4</u>	-	636	А
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	106	W
storage temperature		-55	175	°C
junction temperature		-55	175	°C
peak soldering temperature		-	260	°C
electrostatic discharge voltage	MM (JEDEC JESD22-A115)	430	-	V
diode				
source current	T _{mb} = 25 °C	-	96	А
peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	636	А
gedness				
non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; V_{sup} ≤ 25 V; unclamped; R_{GS} = 50 Ω; see Figure 3	-	60	mJ
	drain-source voltage drain-gate voltage gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature peak soldering temperature electrostatic discharge voltage diode source current peak source current peak source current peak source current non-repetitive drain-source	$\begin{array}{ll} \mbox{drain-source voltage} & 25\ {}^\circ\mbox{C} \le {\rm T}_{\rm j} \le 175\ {}^\circ\mbox{C} \\ \mbox{drain-gate voltage} & 25\ {}^\circ\mbox{C} \le {\rm T}_{\rm j} \le 175\ {}^\circ\mbox{C}; \ {\rm R}_{\rm GS} = 20\ {\rm k}\Omega \\ \mbox{gate-source voltage} \\ \mbox{drain current} & V_{\rm GS} = 10\ {\rm V}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C}; \ {\rm see}\ {\rm Figure}\ 1} \\ \mbox{V}_{\rm GS} = 10\ {\rm V}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C}; \ {\rm see}\ {\rm Figure}\ 1} \\ \mbox{peak drain current} & pulsed; \ {\rm t}_p \le 10\ {\rm \mu}\mbox{s}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C}; \ {\rm see}\ {\rm Figure}\ 1} \\ \mbox{total power dissipation} & {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C}; \ {\rm see}\ {\rm Figure}\ 2} \\ \mbox{storage temperature} \\ \mbox{junction temperature} \\ \mbox{peak soldering temperature} \\ \mbox{electrostatic discharge voltage} & MM\ (JEDEC\ JESD22-A115) \\ \mbox{diode} \\ \mbox{source current} & {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C} \\ \mbox{peak source current} & {\rm pulsed}; \ {\rm t}_p \le 10\ {\rm \mu}\mbox{s}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C} \\ \mbox{peak source current} & {\rm pulsed}; \ {\rm t}_p \le 10\ {\rm \mu}\mbox{s}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C} \\ \mbox{peak source current} & {\rm pulsed}; \ {\rm t}_p \le 10\ {\rm \mu}\mbox{s}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C} \\ \mbox{peak source current} & {\rm pulsed}; \ {\rm t}_p \le 10\ {\rm \mu}\mbox{s}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C} \\ \mbox{peak source current} & {\rm pulsed}; \ {\rm t}_p \le 10\ {\rm \mu}\mbox{s}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C} \\ \mbox{peak source current} & {\rm pulsed}; \ {\rm t}_p \le 10\ {\rm \mu}\mbox{s}; \ {\rm T}_{\rm mb} = 25\ {}^\circ\mbox{C} \\ \mbox{peak source current} & {\rm pulsed}; \ {\rm t}_p \le 10\ {\rm V}\ {\rm T}_{\rm (init)} = 25\ {}^\circ\mbox{C}; \ {\rm l}_{\rm p} = 100\ {\rm A}; \\ \ {\rm V}_{\rm sup} \le 25\ {\rm V}; \ {\rm unclamped}; \ {\rm R}_{\rm S} = 50\ {\rm \Omega}; \end{aligned} \end{cases}$	$\begin{array}{llllllllllllllllllllllllllllllllllll$	$\begin{array}{cccc} drain-source voltage & 25 \ ^{\circ}\text{C} \leq \text{T}_{j} \leq 175 \ ^{\circ}\text{C} & - & 25 \\ drain-gate voltage & 25 \ ^{\circ}\text{C} \leq \text{T}_{j} \leq 175 \ ^{\circ}\text{C}; \ \text{R}_{\text{GS}} = 20 \ \text{k}\Omega & - & 25 \\ gate-source voltage & -20 & 20 \\ drain current & V_{\text{GS}} = 10 \ \text{V}; \ \text{T}_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see Figure 1} & 11 & - & 100 \\ \hline V_{\text{GS}} = 10 \ \text{V}; \ \text{T}_{mb} = 100 \ ^{\circ}\text{C}; \ \text{see Figure 1} & 11 & - & 100 \\ \hline peak \ drain \ current & pulsed; \ t_{p} \leq 10 \ \mu\text{s}; \ \text{T}_{mb} = 25 \ ^{\circ}\text{C}; \ \ see \ \text{Figure 1} & 11 & - & 100 \\ \hline peak \ drain \ current & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see \ Figure 2} & - & 106 \\ \ \text{storage temperature} & -55 & 175 \\ \ \text{junction temperature} & -55 & 175 \\ \ peak \ \text{soldering temperature} & -55 & 175 \\ \ peak \ \text{soldering temperature} & -& 260 \\ \ \text{electrostatic \ discharge \ voltage & MM \ (JEDEC \ JESD22-A115) & 430 & - \\ \ \ \text{diode} & & & & & & & & & & & & & & & & & & &$

[1] Continuous current is limited by package.

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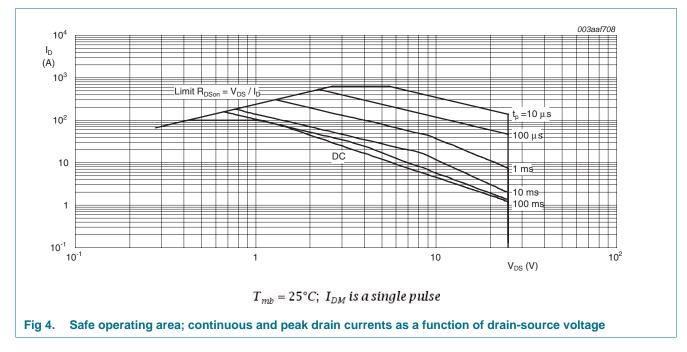
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6. Thermal characteristics

Table 6.Thermal characteristics

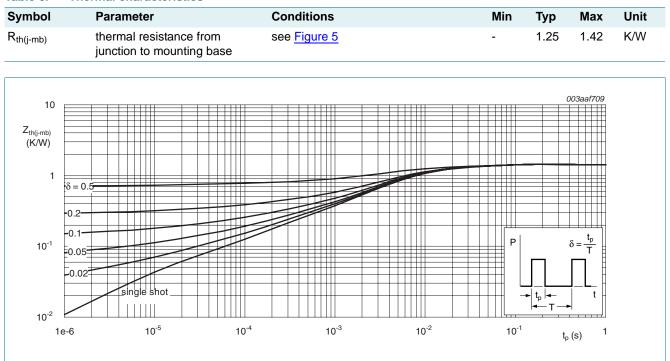


Fig 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

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7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
-	acteristics			.76		
V _{(BR)DSS}	drain-source	I _D = 250 μA; V _{GS} = 0 V; T _i = 25 °C	25	-	-	V
- (BR)D33	breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_i = -55 \ ^{\circ}\text{C}$	22.5	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see Figure 10; see Figure 11	1.05	1.54	1.95	V
	0	$I_{\rm D} = 10 \text{ mA; } V_{\rm DS} = V_{\rm GS}; T_{\rm i} = 150 \text{ °C}$	0.5	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_i = -55 \text{ °C}$	-	-	2.25	V
I _{DSS}	drain leakage current	V _{DS} = 25 V; V _{GS} = 0 V; T _i = 25 °C	-	-	1	μA
		V _{DS} = 25 V; V _{GS} = 0 V; T _j = 150 °C	-	-	100	μA
I _{GSS}	gate leakage current	V _{GS} = 16 V; V _{DS} = 0 V; T _i = 25 °C	-	-	100	nA
		V _{GS} = -16 V; V _{DS} = 0 V; T _i = 25 °C	-	-	100	nA
R _{DSon} drain-source on- resistance	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 12	-	2.6	3.15	mΩ
		V_{GS} = 4.5 V; I _D = 25 A; T _j = 150 °C; see <u>Figure 13</u> ; see <u>Figure 12</u>	-	-	5.05	mΩ
		V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; see <u>Figure 12</u>	-	2	2.4	mΩ
		V _{GS} = 10 V; I _D = 25 A; T _j = 150 °C; see <u>Figure 13</u> ; see <u>Figure 12</u>	-	-	3.85	mΩ
R _G	gate resistance	f = 1 MHz	-	0.9	1.8	Ω
Dynamic c	haracteristics					
Q _{G(tot)}	$Q_{G(tot)}$ total gate charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 14</u> ; see <u>Figure 15</u>	-	39	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see <u>Figure 15</u> ; see <u>Figure 14</u>	-	18	-	nC
						nC
		$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}$	-	38	-	no
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	38 6.3	-	nC
Q _{GS} Q _{GS(th)}	gate-source charge pre-threshold gate-source charge					
Q _{GS(th)}	pre-threshold	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	6.3	-	nC
Q _{GS(th)} Q _{GS(th-pl)}	pre-threshold gate-source charge post-threshold	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	6.3 4.1	-	nC nC
Q _{GS(th)} Q _{GS(th-pl)} Q _{GD}	pre-threshold gate-source charge post-threshold gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	6.3 4.1 2.2	-	nC nC nC
$Q_{GS(th)}$ $Q_{GS(th-pl)}$ Q_{GD} $V_{GS(pl)}$	pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau	$I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 14; see Figure 15 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 14};$ see Figure 15 $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	6.34.12.25.2	-	nC nC nC nC
	pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 14; see Figure 15 $I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 14};$ see Figure 15	-	 6.3 4.1 2.2 5.2 2.7 	-	nC nC nC V
Q _{GS} (th) Q _{GS} (th-pl) Q _{GD} V _{GS} (pl) C _{iss} C _{oss}	pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage input capacitance	$I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 14; see Figure 15 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; \text{ see Figure 14};$ see Figure 15 $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	 6.3 4.1 2.2 5.2 2.7 2542 	- - - -	nC nC nC V pF
$Q_{GS}(th)$ $Q_{GS}(th-pl)$ Q_{GD} $V_{GS}(pl)$ C_{iss} C_{oss} C_{rss}	pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage input capacitance output capacitance reverse transfer	$I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 14; see Figure 15 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; see Figure 14};$ see Figure 15 $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; see Figure 16$ $V_{DS} = 12 \text{ V}; R_{L} = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	 6.3 4.1 2.2 5.2 2.7 2542 617 	- - - -	nC nC nC v v
Q _{GS} (th) Q _{GS} (th-pl) Q _{GD} V _{GS} (pl) C _{iss}	pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-drain charge gate-source plateau voltage input capacitance output capacitance reverse transfer capacitance	$I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 14; see Figure 15 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; see Figure 14};$ see Figure 15 $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; see Figure 16}$	-	 6.3 4.1 2.2 5.2 2.7 2542 617 216 	- - - - -	nC nC nC V pF pF
Q _{GS} (th) Q _{GS} (th-pl) Q _{GD} V _{GS} (pl) C _{iss} C _{oss} C _{rss} td(on)	pre-threshold gate-source charge post-threshold gate-source charge gate-drain charge gate-source plateau voltage input capacitance output capacitance reverse transfer capacitance turn-on delay time	$I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ see Figure 14; see Figure 15 $I_{D} = 25 \text{ A}; V_{DS} = 12 \text{ V}; see Figure 14};$ see Figure 15 $V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}; see Figure 16$ $V_{DS} = 12 \text{ V}; R_{L} = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	 6.3 4.1 2.2 5.2 2.7 2542 617 216 24 	- - - - - - -	nC nC nC V PF pF pF

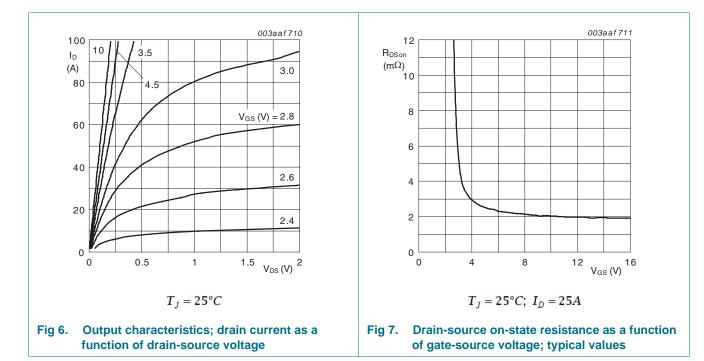
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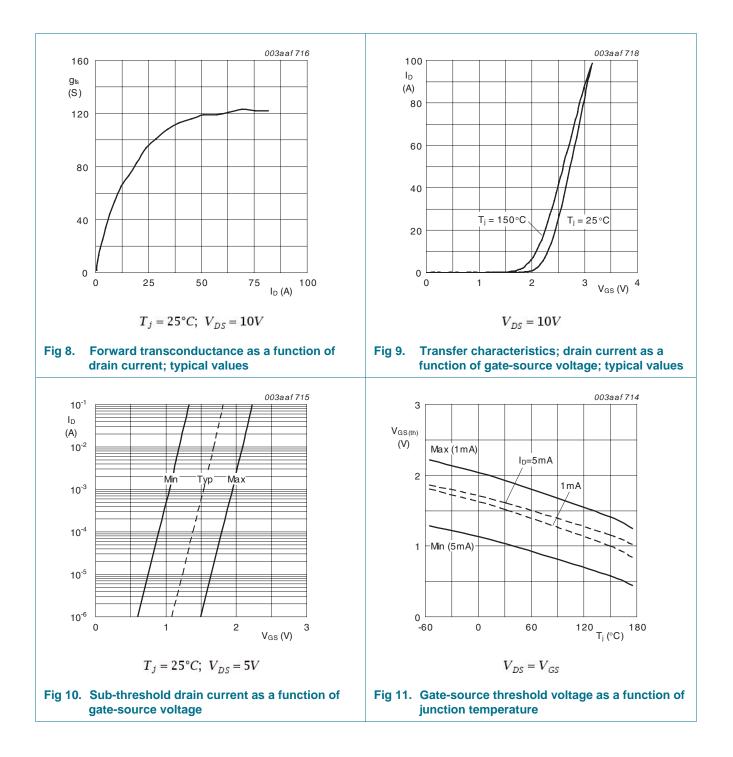
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Table 7.	Characteristics continued					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Q _{oss}	output charge	$V_{GS} = 0 \text{ V}; V_{DS} = 12 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 ^{\circ}\text{C}$	-	16.7	-	nC
Source-d	rain diode					
V_{SD}	source-drain voltage	I _S = 25 A; V _{GS} = 0 V; T _j = 25 °C; see <u>Figure 17</u>	-	0.8	1.1	V
t _{rr}	reverse recovery time	$I_{S} = 25 \text{ A}; \text{ dI}_{S}/\text{dt} = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = 0 \text{ V};$	-	35	-	ns
Q _r	recovered charge	$V_{DS} = 12 V$	-	31	-	nC
t _a	reverse recovery rise time	V _{GS} = 0 V; I _S = 25 A; dI _S /dt = -100 A/µs; V _{DS} = 12 V; see <u>Figure 18</u>	-	21	-	ns
t _b	reverse recovery fall time		-	14	-	ns



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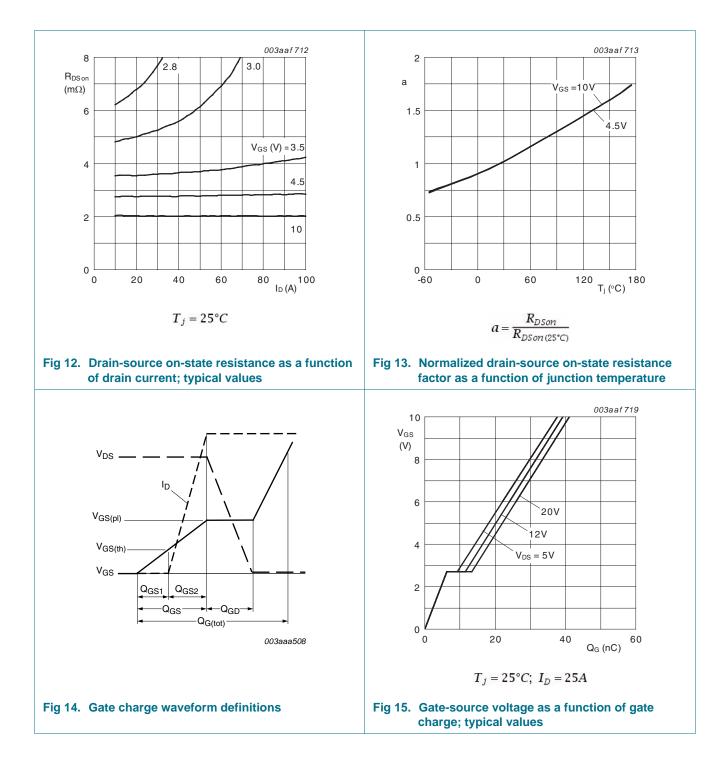


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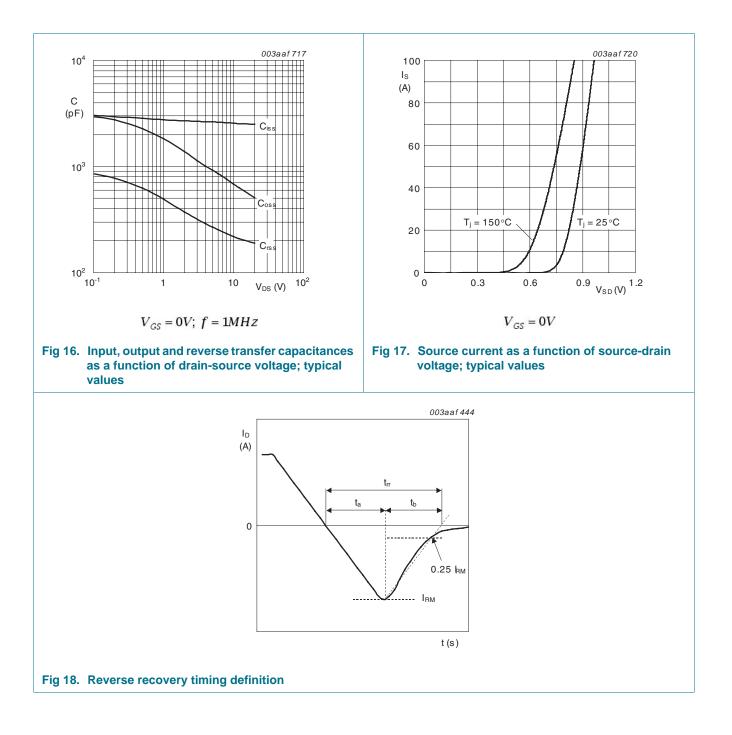
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N-channel 25 V 2.4 mΩ logic level MOSFET in LFPAK using NextPower



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N-channel 25 V 2.4 mΩ logic level MOSFET in LFPAK using NextPower

8. Package outline

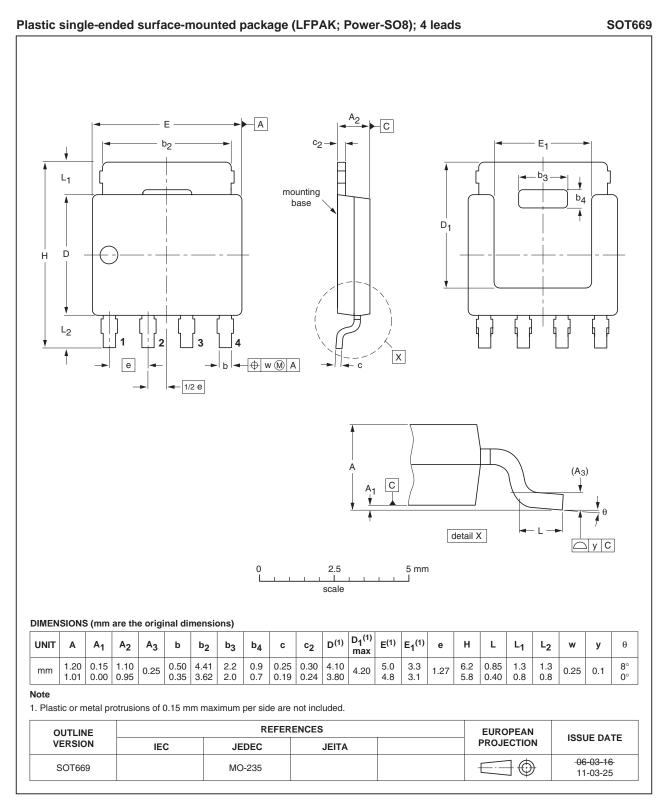


Fig 19. Package outline SOT669 (LFPAK; Power-SO8)

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9. Revision history

Table 8. Revision h	Revision history					
Document ID	Release date	Data sheet status	Change notice	Supersedes		
PSMN2R2-25YLC v.1	20110502	Product data sheet	-	-		

N-channel 25 V 2.4 mΩ logic level MOSFET in LFPAK using NextPower

10. Legal information

10.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <u>http://www.nxp.com</u>.

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Product data sheet

PSMN2R2-25YLC

N-channel 25 V 2.4 m Ω logic level MOSFET in LFPAK using NextPower

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